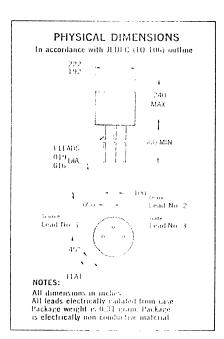
New Jersey Semi-Conductor Products, Inc.

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ABSOLUTE MAXIMUM RATINGS (Note 1)

Storage	emperatures 3 Junction Temperature Temperature 3 Temperature (10 second time limit)	125°C —55°C to +125°C 260°C		
	ower Dissipation sipation at 25°C Ambient Temperature (Note 2)	0.2 Watt		
Maximum Vo	oltages			
V_{SG}	Source to Gate Voltage	25 Volts		
V _{DS}	Drain to Source Voltage	25 Volts		
٧ _{0.5} ,	Drain to Gate Voltage	25 Volts		
I_{G} .	Gate Current	50 mA		



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

SYMBOL	CHARACTERISTICS	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS	
Y _{fs}	Forward Transadmittance ($f = 1.0 \text{ kHz}$)	2,000	6,000	9,000	μmhos	V _{DS} == 15 V	V _{c,5} 0
Re(Y ₅₀)	Forward Transconductance ($f = 1.0 \text{ MHz}$)	1,300	5,500	·		$V_{1.5} = 15 \text{ V}$	V 0
e _n	Equivalent Input Noise Voltage		12	50		V _{D5} == 15 V	I. 1.0 mA
	(f = 1.0 kHz, BW = 150 Hz)				•	05	-D
NF	Noise Figure (f = 1.0 kHz, $R_G = 150 \text{ k}\Omega$, BW = 150 Hz)			3.0	dB	$V_{c.r} := 15 \text{ V}$	I 1.0 mA
NF	Noise Figure (f = 1.0 kHz, $R_G = 1.0 \text{ M}\Omega$, BW == 150 Hz)		< 0.1		dB	V _{DS} == 15 V	I _D 1.0 mA
r _{ds(on)}	Drain "On" Resistance (f = 1.0 kHz)		125	500	olims	V _{C-5} = . 0	I _r ,0
I _{DSS}	Drain Current	1.0	14	40	mA	$V_{\rm int} = 15 \text{ V}$	V 0
V _{GS(off)}	Gate to Source Cutoff Voltage	0.4	-3.7	-3.0	Volts	V _D == 15 V	Ι ₀ 1.0 μΑ
V_{GS}	Gate to Source Voltage		-3.5	-7.5	Volts	$V_{tris} = 15 \text{ V}$	1. 100 μΑ
IGSS	Gate Reverse Current		0.1	10		V _{C-5} == =15 V	V _{D5} = 0
I _{G55} (85°C)	Gate Reverse Current		0.03	0.6	μΛ	V _{CC} == -15 V	V 0
C _{rs} ,	Reverse Transfer Capacitance ($f = 1.0 \text{ MHz}$)		1.3	3.0	ρF	V _{r.0} == 15 V	
Ciss	Input Capacitance (f = 1.0 MHz)		8.7	12	ρF	V ₁₀ = 15 V	
Yos	Output Admittance (f = 1.0 kHz)		60	200	umhos	V _{1.7} = 15 V	V . 0
BV _{GSS} .	Gate to Source Breakdown Voltage	25			Volts	V _{1.7.} == 0	1 10 μΑ

NOTES

⁽¹⁾ These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.

⁽²⁾ These ratings give a maximum junction temperature of 125°C and junction to ambient thermal resistance of 500°C/Watt (denating factor of 2.0 mW = 6.